

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BADEJO ET AL.	
		Examiner Jennifer A. Leung	Art Unit 1764	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,328,170	05-1982	Okawara et al.	558/372
	B	US-3,903,055	09-1975	Buck, Carl J.	526/194
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 59226075 A	12-1984	Japan	SHIIINA et al.	C09J 03/14
	O	JP 11049195 A	02-1999	Japan	TAKAHASHI et al.	B65D 35/02
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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